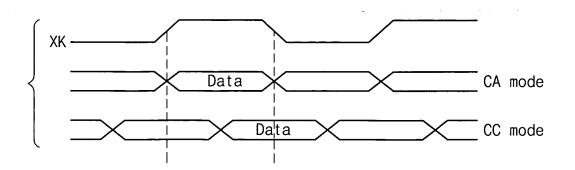
Fig. 1

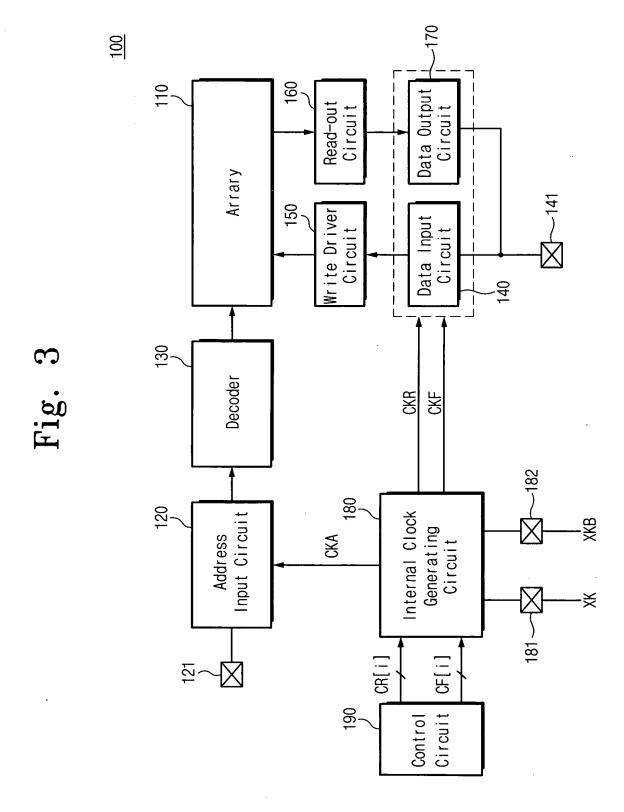
Operating Frequency Range
of Memory Device

Operating Frequency Range
of Test Equipment

Synchronization Range

Fig. 2





98 SMDR • • • <u>E</u> <u>B</u> 8 -1221T-(td1+td2+td3+td4) 1+T/8 td2 CLK_01 Fig. 4A CLK_45T REGEN 1190 CR[i] td4 1150 M **00T1** 0UT2 **0UT3** 1140 BR√ td3 1200 DRV 1130 ΧM CLKref1 1120 OUT1R + OUT2R + OUT3R + OUTIR OUTZF td4 REGEN 1110

 ~ 1370 ~1380 ~1420 ~ 1430 180 SMPF ß В 8 -1421T-(td1+td2+td3+td4) 1+1/8 H td2 | CLK 901 Fig. 4B CLK_135T td4 REGEN 1390 CF[i] 1350 ¥ td3 **0UT2** 0UT1 1340 DRV 1330 CLKref2 1400 td2 DRV ¥ -0UT3R -0UT3F E] 1320 0UT1F ▲ 0UT2F ▲ 0UT3F -OUT2R OUT1F 1500 REGEN tot 45 REGEN 뎔 td4 1310 1410-

Fig. 5

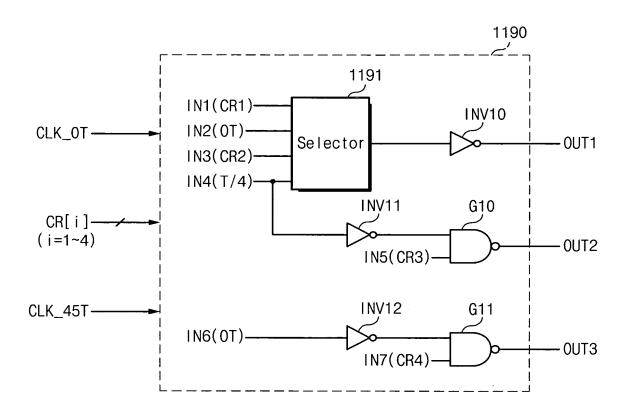


Fig. 6

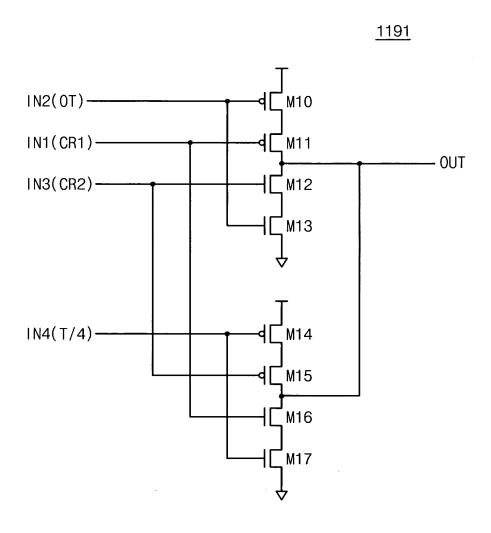


Fig. 7A

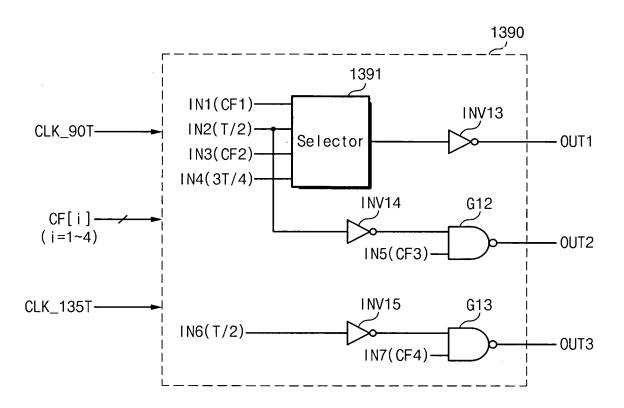


Fig. 7B

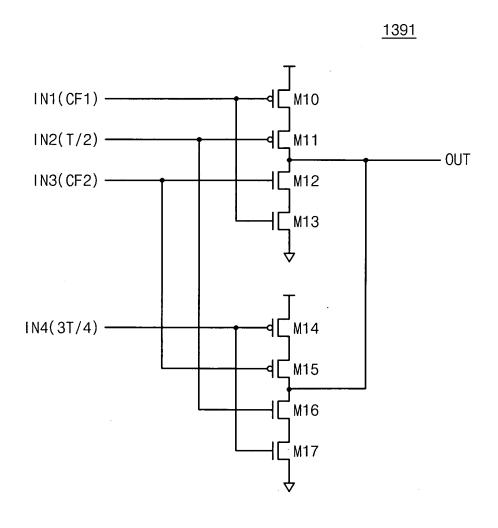
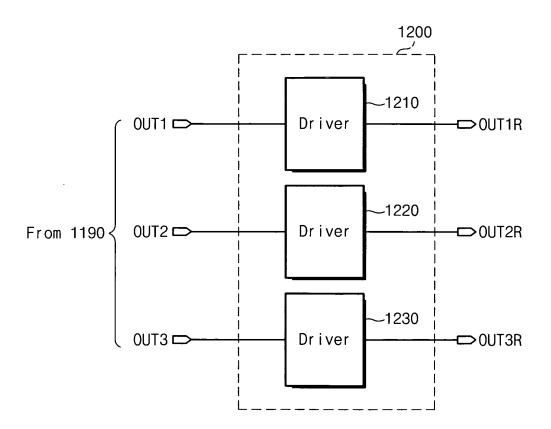
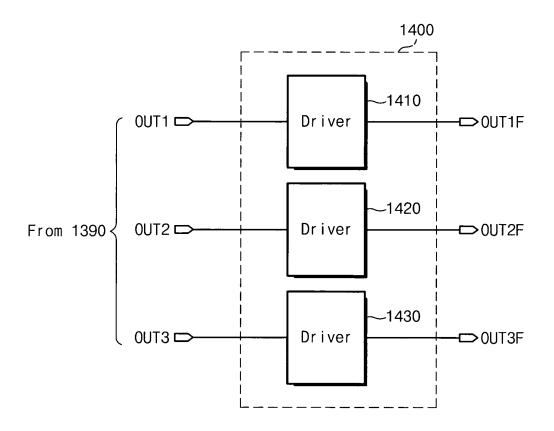


Fig. 8



1210,1220,1230 _M28 ω. INV24 Fig. 9 M25 M19 A 1N/21 INV16

Fig. 10



1250 -4[M40 ~INV26 ~INV28 INV32 Fig. 11 IN/31 1N/30 1NV29 M30] M36_] <u>G</u>14 OUT1R DOUT2F DO

Fig. 12

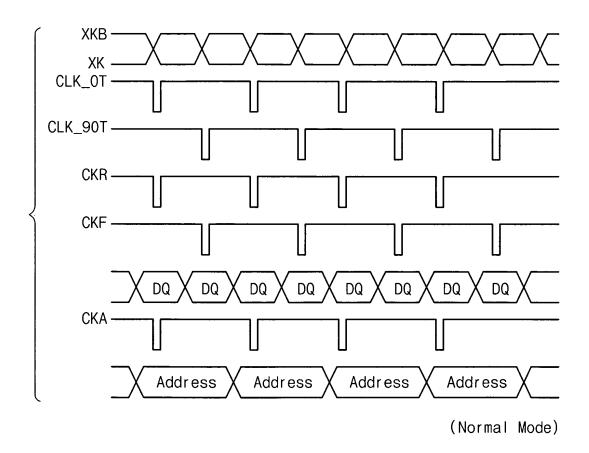
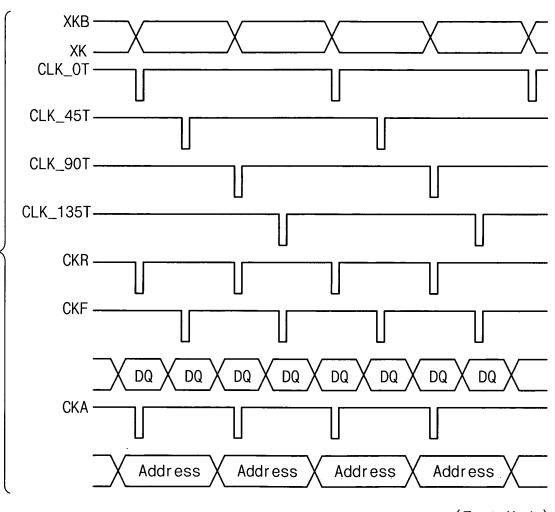


Fig. 13



(Test Mode)